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PREAMPLIFIER STAGE OF LVDS RECEIVER

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Abstract: Ever increasing demands of The processing speeds require very high speed and power efficient interconnections between the ICs. Such connections are governed by various standards, LVDS is one among them. In order to meet the requirements of high speed, low noise communication between ICs, the Low Voltage Differential signalling (LVDS) protocol is used. This paper studies the design of preamplifier stage of LVDS receiver. Due to the differential transmission technique and the low voltage swing, LVDS allows high transmission speeds and low power consumption at the same time.

Keywords: LVDS, differential amplifier, CS amplifier

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INTRODUCTION

Board level chip interfaces are demanding very high speed, power efficient interfaces. The ever increasing processing speed of microprocessor motherboards, optical transmission links, intelligent hubs and routers, etc..., pushing the off-chip data rate into the gigabits-per second range. However, unlike internal clocks, chip-to-board signaling gains little benefit in terms of operating frequency from the increased silicon integration. In the last decade, high data rates were achieved by massive parallelism, with the disadvantages of increased complexity and cost for the IC package and the printed circuit board (PCB). For this reason, the off-chip data rate is expected to move to the range of Gb/s-per-pin in the near future.[2] [3]

While the reduction of the power consumption is of great concern in battery-powered portable systems, it is also required in other systems to reduce the costs related to packaging and additional cooling systems. Some of today's biggest challenges that remain to be solved include: the ability to transfer data at fastest rate possible, low power systems than currently available and economical solutions to overcome the physical layer bottleneck.

Data transmission standards like RS-422, RS-485, SCSI and others have their own limitations notably in transferring raw data across a medium. Optical fibers are also costly and area inefficient for long distances. Thus, low-cost, high-speed parallel links and serial links using copper cables are an attractive solution for such applications. In this regard, Low-voltage Differential Signaling (LVDS) technology was developed in order to provide a low-power and low-voltage alternative, to other high-speed I/O interfaces for point-to point transmission.[4][5]

1.1) Preamplifier

This stage of the LVDS receiver is to reject the common mode noise. Hence, too much of amplification is not necessary, but a very good bandwidth is required. Therefore, a very good differential amplifier along with ESD protection circuit is used to welcome the incoming signal at the receiver side.

The amplifier stage is responsible for accommodating a very wide range of common mode signal; this is because the signal travelling long distances (from transmitter to receiver) will be affected by the external noise. Also, the ground level can shift to a different value. The output signal of the Pre-Amplifier stage has to be a differential signal which is riding on a constant DC signal, in order to bias the next stage of the receiver circuit.

FOLDED CASCODE DIFFERENTIAL AMPLIFIER

2.1) Architecture

Folded Cascode has a special kind of arrangement in terms of the flow of current in the amplifier circuit. The CS amplifier (M1 and M2) acts as the voltage to current converter in the circuit, here the CS amplifier has the source degeneration resistor, i.e. the current source M3, gate to drain resistance(r_{ds2}). The converted current is folded and pushed into the CG amplifier (M6 and M7) whose load is the series combination of resistance (R1 and R2) and the MOS diode (M8 and M9). The amplified current following through the MOS diode and the resistance load produce the output voltage with the load capacitor (CL). The figure 4.1 gives the folded cascode differential amplifier which is used in this project. The MOS diode is used as the load. The diode along with the resistance will provide less resistive load, but the bandwidth is improved, along with this, the drop across the resistance, which means less variation of voltage across the resistance if there is variation of resistance.

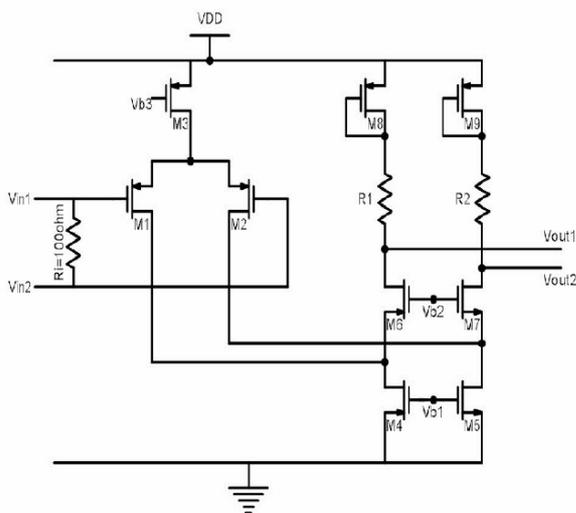


Fig 2.1 Folded Cascode Differential Amplifier circuit

2.2) Electrical Specification for Preamplifier

All the specifications of the system are derived in accordance with the IEEE 1596.3 - 1996 Std.[1]

Input common mode voltage =50mV to 2.35 V.

Input differential voltage=-100mV to +100mV.

-
Output common mode voltage=1.65V.

Output differential voltage=+300mV to -300 mV.

load capacitor=20fF.

Slew rate=2V/nsec.

$$S=I_3/C_I$$

PMOS design The current owing in pmos transistor

$$I_3=S \cdot C_I$$

$$I_3=(2V/nsec) \cdot (20fF)$$

$$I_3=40\mu A$$

$$I_2 \text{ or } I_1=I_3/2$$

$$I_2 \text{ or } I_1=40\mu A/2$$

$$I_2 \text{ or } I_1=20\mu A$$

Take $V_{in1}=V_{in2}=50mV$ to 2.35V.

$$R_{in}=100\text{ohm}$$

Take $V_{gs}=V_{b1}$

current owing in PMOS

$$I_4 \text{ and } I_5=1.5 \cdot I_1$$

$$I_4 \text{ and } I_5 = 1.5 \cdot 40\mu A$$

$$I_4 \text{ and } I_5 = 60\mu A$$

$$I_4=I_5=30\mu A$$

$$I_1+I_2=I_3+I_4$$

$$I_1+I_2-I_3-I_4=0$$

$$I_6 \text{ and } I_7= (I_4 \text{ or } (I_5)-I_1)$$

I_6 and $I_7 = (60\mu A - 20\mu A)$

I_6 and $I_7 = 40\mu A$

V_{out1} and $V_{out2} = 3.3/2 = 1.65V$

Take V less than V_{out}

so $V = .04V$

$R_{in} = .04/40\mu A$

$R_{in} = 1K\Omega$

We need to calculate M_8 and M_9

so, V_8 and $V_9 = (V_{out} - V_{rl})$

V_8 and $V_9 = 1.65 - .08$

V_8 and $V_9 = 1.57V$

V_{gs} and $V_{ds} = 1.57V$

PMOS design

To calculate the M_8 and M_9 W_8/L_8 values

$I = [\mu_n \cdot C_{ox} \cdot (W_8/L_8)_p \cdot (V_{gs} - V_{th})^2]$

$V_{gs} = 1.57V$

$V_{th} = .7V$

$C_{ox} = \epsilon_{ox}/t_{ox}$

$C_{ox} = (3.9 \cdot 8.854) / (2)$

$C_{ox} = 1.726 F/cm^2$

$\mu_p = 500 cm^2/Vsec$

I_6 and $I_7 = 40\mu A$

For M_8 and M_9

$$I_6 = \mu_n C_{ox} \left(\frac{W_8}{L_8} \right) (V_{gs} - V_{th})^2$$

$$I_6 = 40 / (500 \times 1.726 \times 10^{-7})$$

$$\left(\frac{W_8}{L_8} \right) = 40 / 750.81$$

$$\left(\frac{W_8}{L_8} \right) = 50 \mu\text{m}$$

NMOS design

M4 and M5

$$V_{b1} = 2V$$

$$I_4 \text{ and } I_5 = 60 \mu\text{A}$$

$$I_4 = \mu_n C_{ox} \left(\frac{W_4}{L_4} \right) n (V_{gs} - V_{th})^2$$

$$60 \mu\text{A} = [637.51 \times 1.726 \times \left(\frac{W_4}{L_4} \right) n \times (2 - 0.7)^2]$$

$$\left(\frac{W_4}{L_4} \right) n = 60 \mu\text{A} / 637.51 \times 1.726 \times 1.69$$

$$\left(\frac{W_4}{L_4} \right) n = 40 \mu\text{m} \text{ For nmos transistors M6 and M7}$$

Take $\mu_n = 3.142 \text{ cm}^2/\text{Vsec}$

$$I_6 = \mu_n C_{ox} \left(\frac{W_6}{L_6} \right) n (V_{gs} - V_{th})^2$$

$$40 = [3.142 \times 1.172 \times \left(\frac{W_6}{L_6} \right) n \times (1.8 - 0.7)^2]$$

$$\left(\frac{W_6}{L_6} \right) n = [40 / (3.142 \times 1.172 \times 1.1)]$$

$$\left(\frac{W_6}{L_6} \right) = 20 \mu\text{m}$$

take $\mu_p = 1.142 \text{ cm}^2/\text{Vsec}$ For pmos transistor M3 $I_3 = \mu_p C_{ox} \left(\frac{W_3}{L_3} \right) p (V_{gs} - V_{th})^2$

$$40 \mu = [1.142 \times 1.172 \times \left(\frac{W_3}{L_3} \right) p \times (.49)]$$

$$\left(\frac{W_3}{L_3} \right) p = 40 \mu / [1.142 \times 1.172 \times .49]$$

$$\left(\frac{W_3}{L_3} \right) p = 60 \mu\text{m} \text{ For pmos transistors M1 and M2}$$

$$I_1 = \mu_p C_{ox} \left(\frac{W_1}{L_1} \right) p (V_{gs} - V_{th})^2$$

$$I_1 = [1.142 * 1.172 * (W_1/L_1)_p * (2.4 - 0.7)^2]$$

$$(W_1/L_1)_p = [30 \mu A / (1.141 * 1.172 * 1.7)]$$

$$(W_1/L_1)_p = 20 \mu m$$

2.3) Design Steps

The design steps of the folded cascode differential amplifier are as given below.

Slew Rate-The slew rate required at the output determines the tail current of the differential pair. Therefore $I_{Tail} = 400 \mu A$.

Bias current in Cascode Pair-The bias current following in the cascode pair (M6 and M7) will be nearly equal to the tail current. This defines the W/L ratio of the cascode devices.

Maximum current in the arm-The current from the differential pair and the current from the cascode device together is to be accommodated by the n-MOS, M5 and M6. Hence this defines the W/L ratio of the M5 and M6.

Maximum input common mode voltage range-The maximum input common mode voltage range defines the minimum over-drive voltage that is required to keep the p-MOS M3, hence the W/L of M3 will be defined by the same.

Minimum input common mode voltage range-The minimum input common mode voltage defines the maximum overdrive voltage of the n-MOS M5 and M6, which defines W/L of MOSFETs M5 and M6.

Output Common mode voltage-The output common mode voltage is VDD. **VMOS-Diode** **VResistor-**The voltage drop across the diode is fixed by a constant W/L of MOS. The current owing through the resistor will define the voltage across the resistor. Hence, the resistor value is fixed by the voltage drop required to meet the output common mode specification.

Input resistance-The resistance of 100 is put as the terminating resistance of the LVDS receiver in order to match with the impedance of the transmission line which is 100 as per the IEEE Std 1596.3.[1].

2.4) Bias circuit of the Folded Cascode Differential Amplifier

The Folded Cascode desires a special type of bias network, in order to keep all the MOSFETs in saturation region. The Bias network uses a current reference. The current reference used is

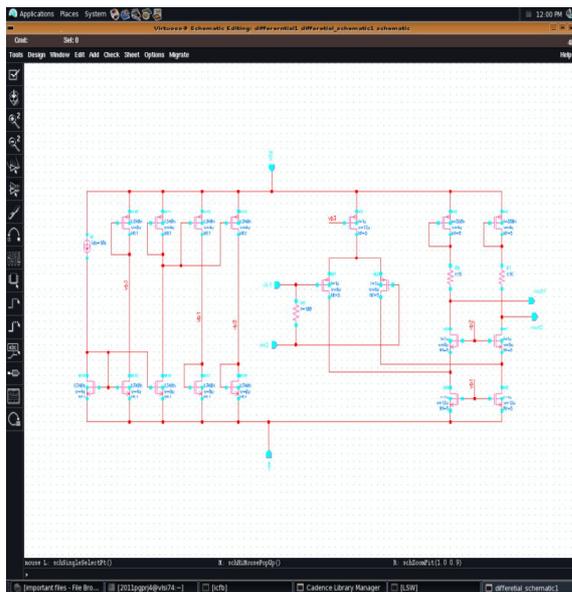


Fig 3.1 The Differential Amplifier Schematic

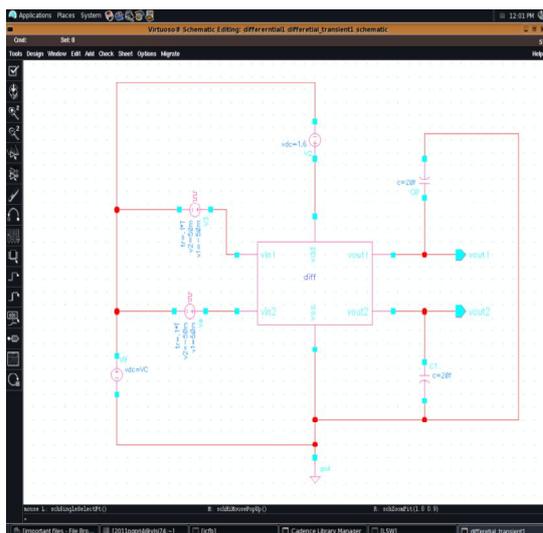


Fig 3.2 The differential transient Schematic

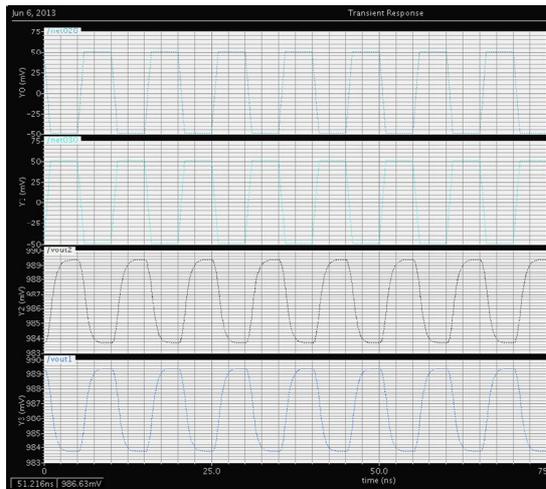


Fig 3.3 The differential transient response output

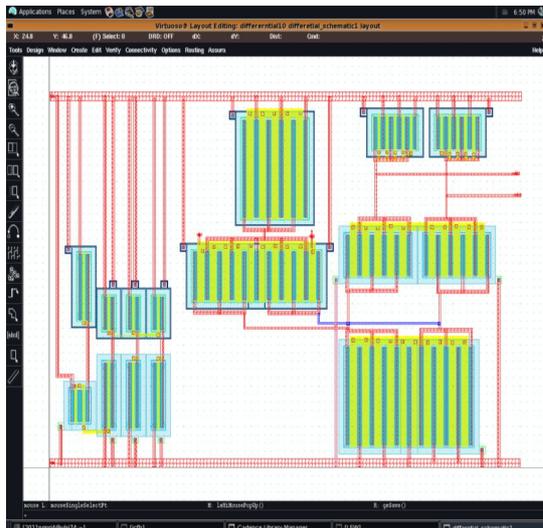


Fig 3.4 layout of the Differential amplifier

CONCLUSION:

In this paper we designed a preamplifier stage of LVDS receiver at 0.18um technology.

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